



Application/Control	No.

Applicant(s)/Patent under Reexamination

10/645,510 Examiner TU, CHUN-YEN Art Unit

David E. Martinez

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SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East (see attached)	11/22/2005	DM	
710/30. 370/470-472. 709/236. 707/100. with keywords and text search	11/22/2005	DM	
Inventon Search through eDan	11/22/2005	DM	
Databases: US Patents, US PGPUBS, USOCR, EPO, Derwen,t IBM_TDB.	11/22/2005	DM	